

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Terunobu MARUYAMA et al.

Application No.: To be Assigned

Group Art Unit: To be Assigned

Filed: November 12, 2003

Examiner: To be Assigned

For: LOGICAL EQUIVALENCE VERIFYING DEVICE, LOGICAL EQUIVALENCE VERIFYING METHOD, AND LOGICAL EQUIVALENCE VERIFYING PROGRAM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:
 - 1a. Form PTO-1449.
 - 1b. Copies of IDS citations.
 - 1c. An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
 - 1d. English language translation (complete or relevant portion(s)) attached to each non-English language publication.
 - 1e. Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.
2. In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is
(Check appropriate Items 2a, 2b, 2c and/or 2d)
 - 2a. satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
 - 2b. set forth in the application.

2c. satisfied because an English language translation (complete or relevant portion(s)) is attached to each non-English language publication.

2d. enclosed as Attachment 1(e), hereto.

3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

STAAS & HALSEY LLP

Dated: 10/12, 2003
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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTORNEY DOCKET NO.
1602.1029APPLICATION NO.
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FIRST NAMED INVENTOR

Terunobu MARUYAMA et al.

FILING DATE

November 12, 2003

GROUP ART UNIT

To be Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA	6,449,750	09/10/02	TSUCHIYA			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO
	AB	05-006403	01/14/93	JAPAN			Partial Translation	
	AC	10-254923	09/25/98	JAPAN			Partial Translation	
	AD	09-044552	02/14/97	JAPAN			Partial Translation	
	AE	2000-207440	07/28/00	JAPAN			Abstract only	
	AF	06-223130	08/12/94	JAPAN			Partial Translation	
	AG	03-157781	07/05/91	JAPAN			Abstract only	
	AH	2001-060216	03/06/01	JAPAN			Abstract only	
	AI	07-085112	03/31/95	JAPAN			Abstract only	
	AJ	04-140885	05/14/92	JAPAN			Abstract only	
	AK	05-225274	09/03/93	JAPAN			Abstract only	
	AL	08-190421	07/23/96	JAPAN			Abstract only	

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

AM	
AN	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.